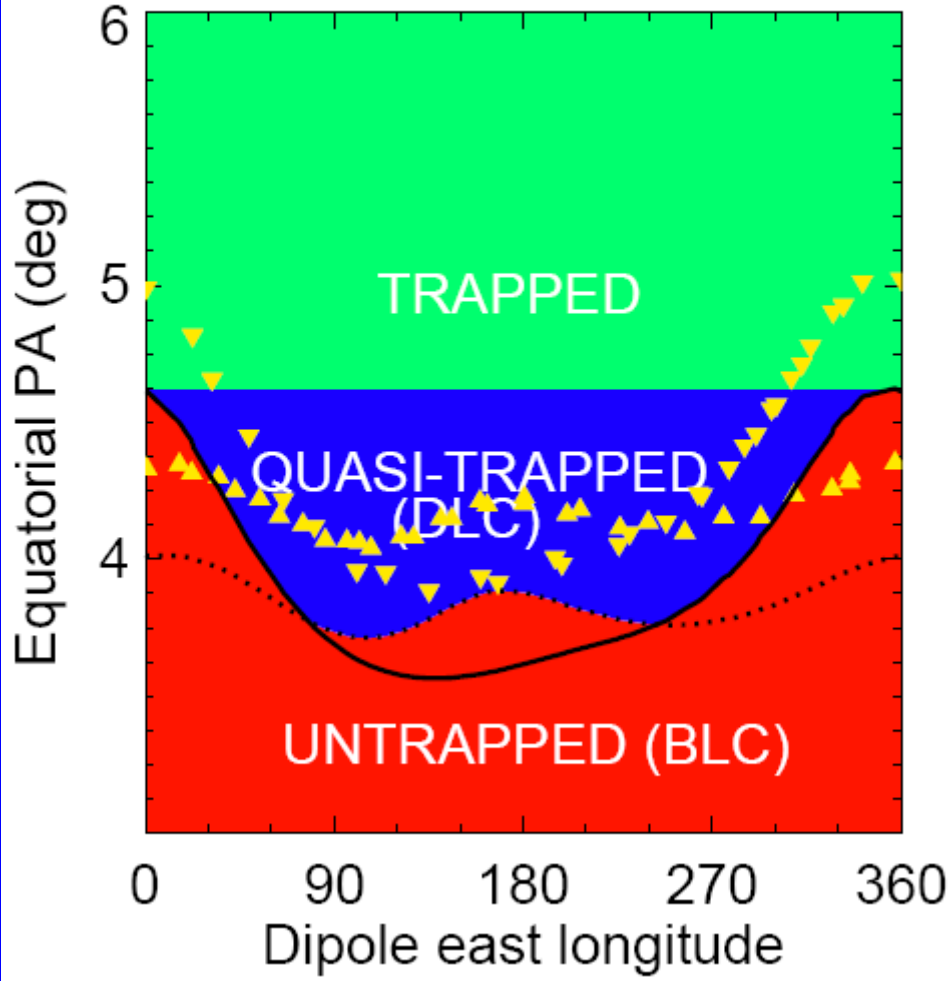
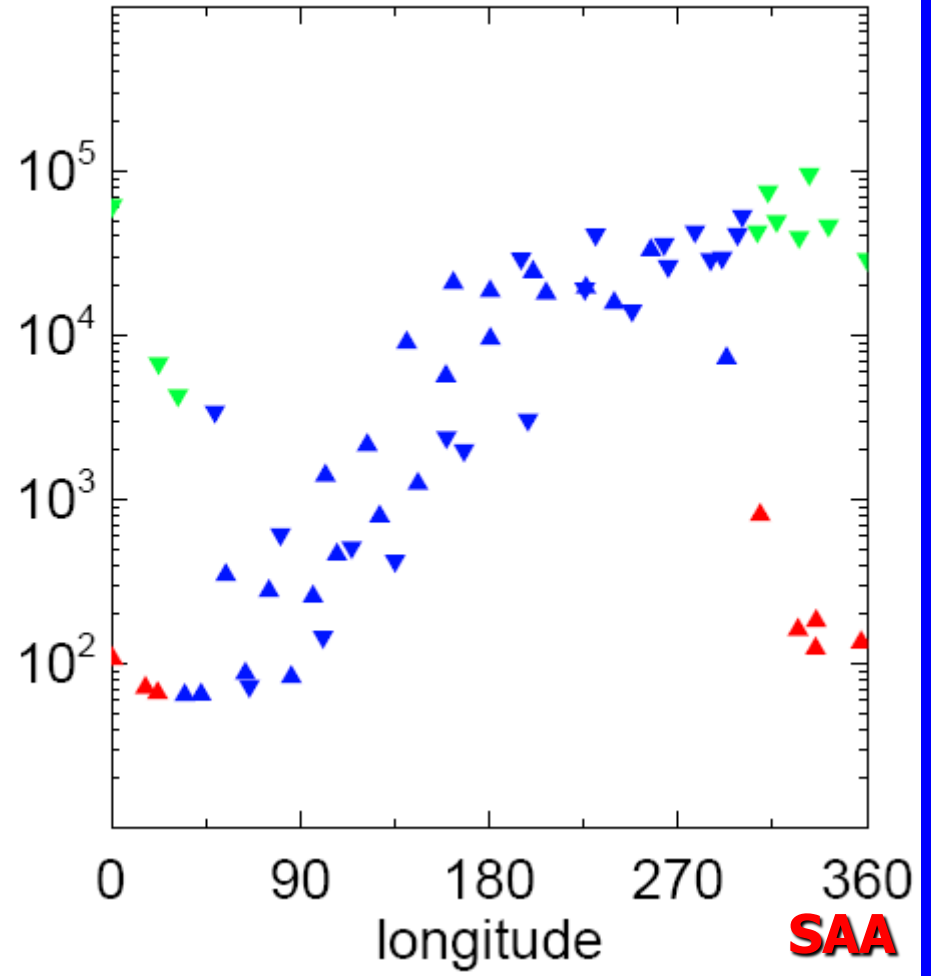


SAMPEX/PET Count Rate Data

CR data at same locations →



P1 (>0.6 MeV) CR[#/6sec]
02/13/2009 at L=5.0



- The relative trapped and quasi-trapped intensities determine the loss rate

Model of the loss rate and source rate

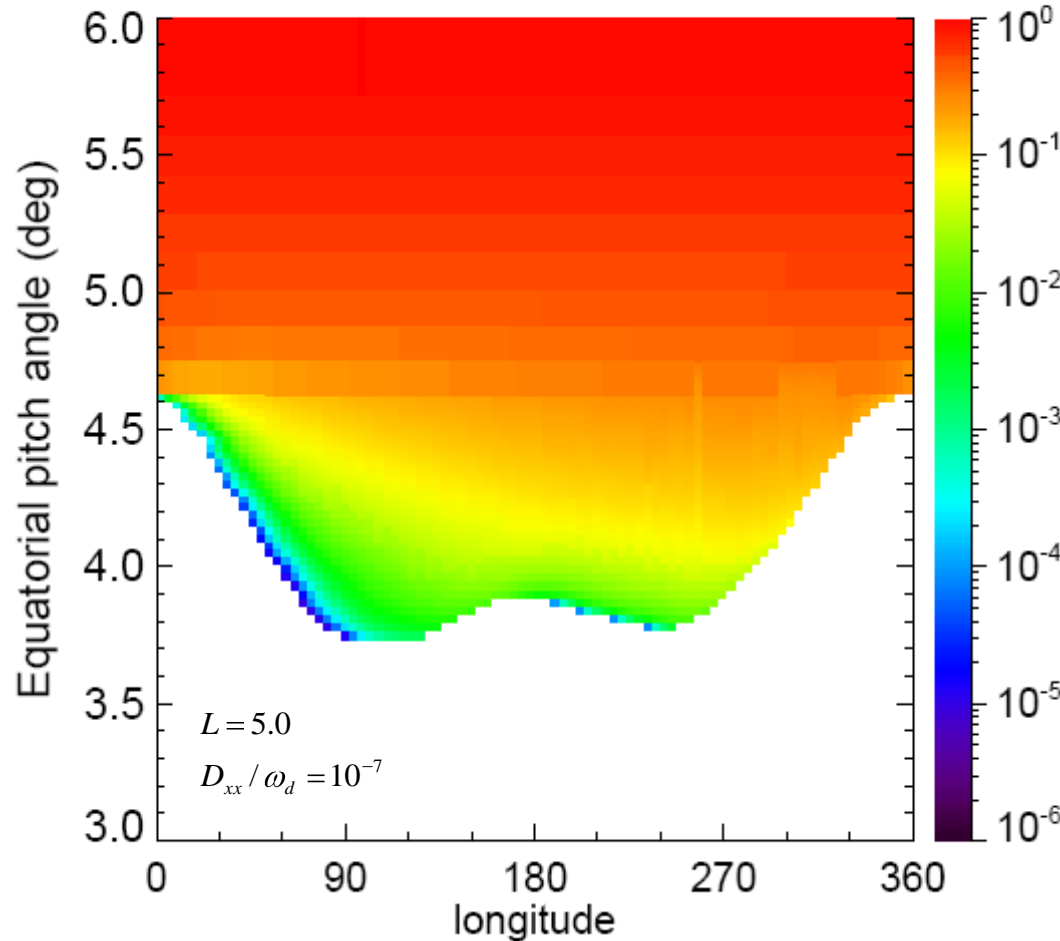
- Low-altitude electron distribution is **a balance of pitch-angle diffusion, azimuthal drift and possible sources**:

$$\text{For given } L \text{ and } E: \frac{\partial f}{\partial t} + \omega_d \frac{\partial f}{\partial \phi} = \frac{\omega_b}{x} \frac{\partial}{\partial x} \left(\frac{x}{\omega_b} D_{xx} \frac{\partial f}{\partial x} \right) + S$$

- Given parameterized D_{xx} and S , this equation can be solved to model the SAMPEX data
- **Outcomes** from the model fit:
 - **Electron loss rate:** $D_{xx} = D_{\text{dawn/dusk}} E^{-a} (10^{-4} + x^{30})^{-1}$, $x = \cos \alpha_0$
 - **Electron source rate:** $S = S_0 E^{-v} g_1(x) / p^2$

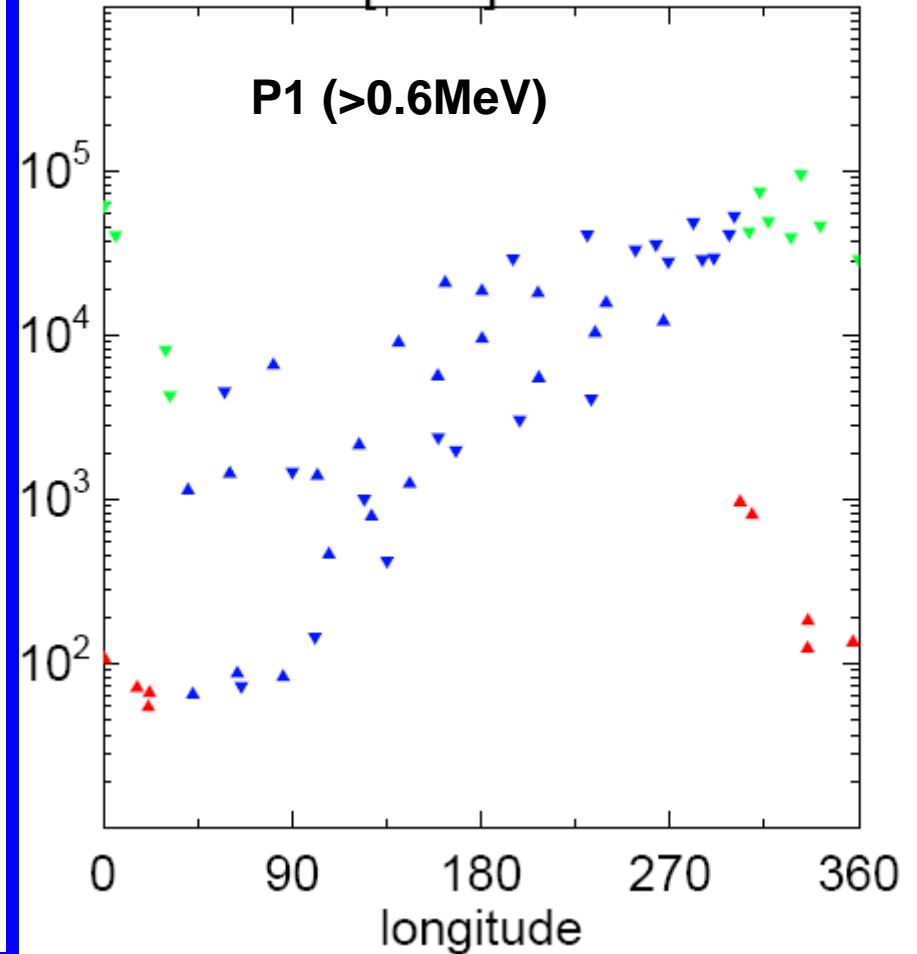
Sample Model Solutions

Normalized electron intensity $f(\alpha, \phi)$



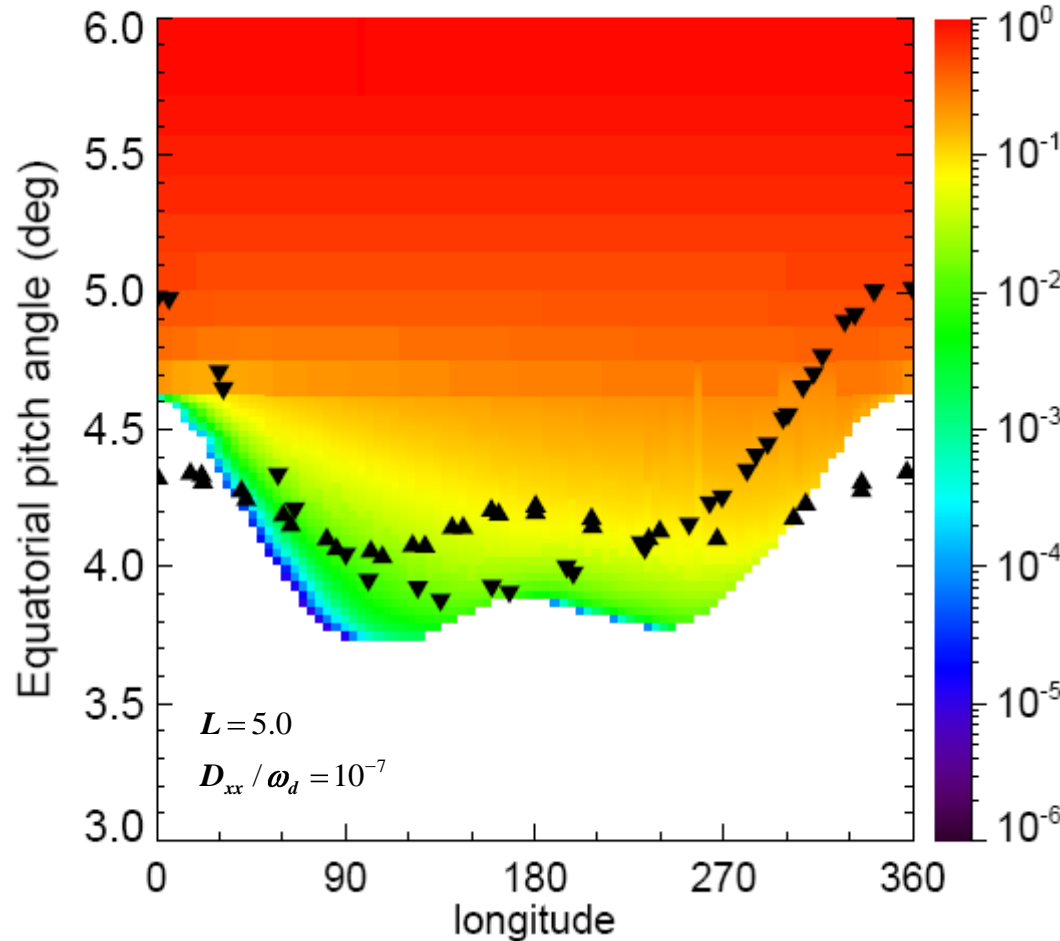
Stably trapped, Quasi-trapped, Untrapped

Count rate [# / 6s] at L=5.0



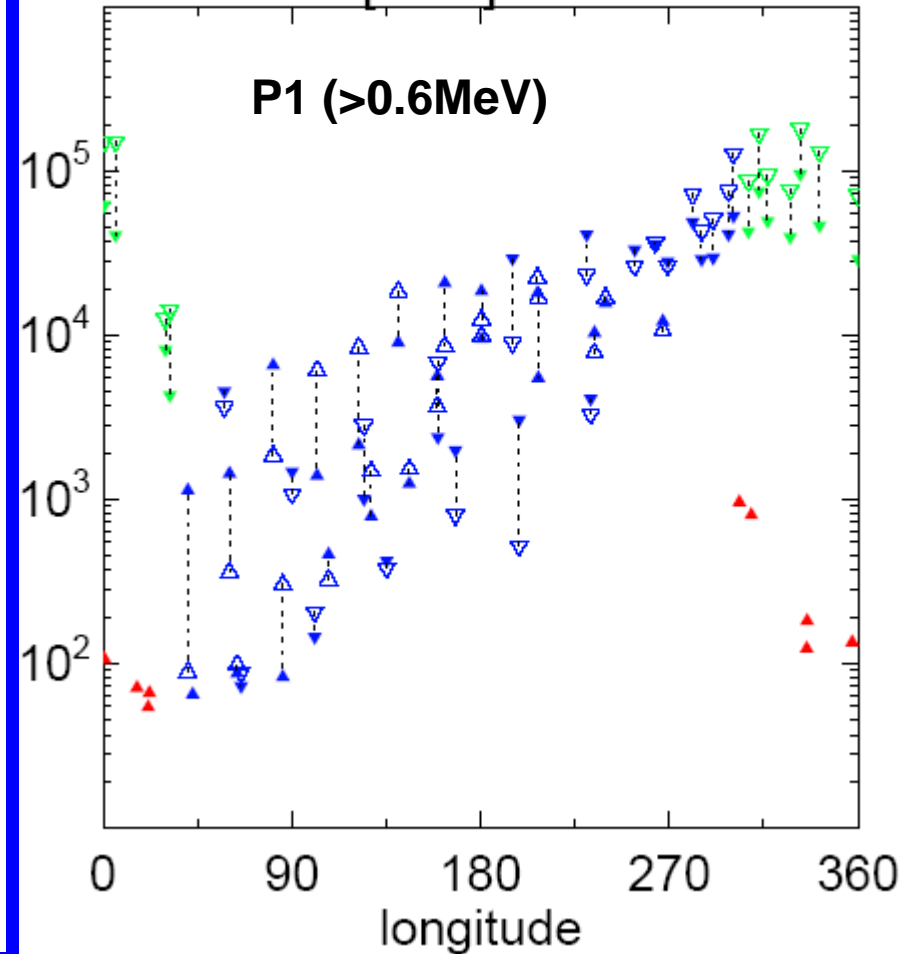
Data and Model Comparison

Normalized electron intensity $f(\alpha, \phi)$



Stably trapped, Quasi-trapped, Untrapped

Count rate [# / 6s] at $L = 5.0$



Model Outcomes

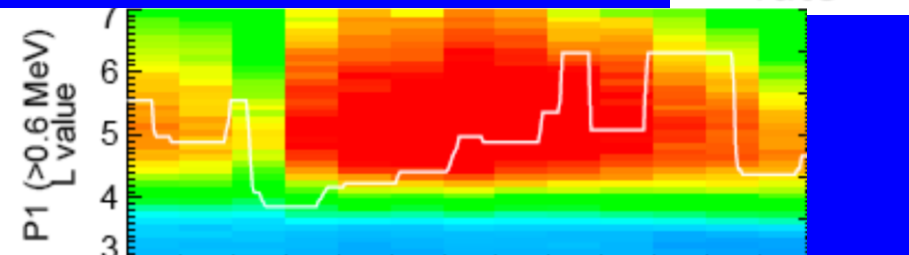
- 6 different energies
- at L=4.5
- Lifetime, energy dependent (~ hr to day).

Trapped electron intensity

Source rate

Lifetime

Replenish-time



SAMPEX data

